Application/Control No. 10/052,570 Applicant(s)/Patent Under Reexamination OTOGAWA ET AL. Examiner Brian L. Mutschler Applicant(s)/Patent Under Reexamination OTOGAWA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,547,600	12-1970	THEMY TIM; et. al.	428/661
	В	US-3,674,656	07-1972	Yates, Charles B.	205/50
	C	US-4,318,794	03-1982	Adler, Edward	204/216
	D	US-4,515,673	05-1985	Hayfield, Peter C. S.	204/196.36
	E	US-5,019,224	05-1991	Denton et al.	205/300
	F	US-5,215,646	06-1993	Wolski et al.	205/77
	G	US-5,407,556	04-1995	Shimada et al.	205/77
	Ή	US-6,527,939	03-2003	Hardee, Kenneth L	205/292
	-	US-6,663,758	12-2003	Motohashi et al.	205/77
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08109490 A	04-1996	Japan	ENDO et al.	C25B 11/10
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	u	
	Ņ	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.